

## TEST REPORT IEC 62471 Photobiological safety of lamps and lamp systems

Total number of pages .....:

Testing Laboratory...... SAMSUNG ELETRONICS Co., Ltd.

Applicant's name ...... SAMSUNG ELETRONICS Co., Ltd.

Address ...... 129, Samsung-ro, Yeongtong-gu, Suwon-si, Gyeonggi-do, 16677,

Korea

Test specification:

Standard...... IEC 62471:2006 (First Edition)

Test Report Form No. ..... IEC62471A

TRF Originator ...... VDE Testing and Certification Institute

Master TRF ...... Dated 2009-05

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This report is not valid as a CB Test Report unless signed by an approved CB Testing Laboratory and appended to a CB Test Certificate issued by an NCB in accordance with IECEE 02.

Test item description .....: LED PKG

Trade Mark ...... SAMSUNG

Manufacturer ...... Same as Testing Laboratory

Model/Type reference ...... SCS8RT78EPL1W0S06E

Ratings ...... DC 500 mA

Page 2 of 4 Report No.: 16-01-07

Testing procedure and testing location:							
	Testing Laboratory:	SAMSUNG ELETRONICS Co., Ltd. (LED Biz.)					
Testing location/ address:		1, Samsung-ro, Giheung-gu, Yongin-si, Gyeonggi-do, 1711; Korea					
	Associated Laboratory:						
Testing location/ address:							
	Tested by (name + signature):						
	Approved by (+ signature):						
	Testing procedure: TMP						
	Tested by (name + signature):						
	Approved by (+ signature):						
Test	ing location/ address:						
	Testing procedure: WMT						
	Tested by (name + signature):						
	Witnessed by (+ signature):						
	Approved by (+ signature):						
Test	ing location/ address:						
	Testing procedure: SMT						
	Tested by (name + signature):						
	Approved by (+ signature):						
	Supervised by (+ signature):						
Test	ing location/ address:						
	Testing procedure: RMT						
	Tested by (name + signature):						
	Approved by (+ signature):						
	Supervised by (+ signature):						
Testing location/ address:							

Page 3 of 4 Report No.: 16-01-07

Summary of testing:									
This product is classified to Exempt group according to IEC standard. But, classified to Risk 1 Group according to EN standard due to different the limit value of small source of blue light hazard.									
Tests performed (name of test and test clause):	Testing location:								
<ul> <li>The sample was applied DC 500mA following by applicant request.</li> <li>The sample was measured at 25°C.</li> </ul>	SAMSUNG ELETRONICS Co., Ltd 1, Samsung-ro, Giheung-gu, Yongin-si, Gyeonggi-do, 17113, Korea								
Summary of compliance with National Differences	<u>.</u>								
January or compliance than handles 2 more									
The sample(s) tested complies with the requirements of IEC 62471:2006 and EN 62471:2008.  See Attachment at the end of this report for compliance with European Group Difference and National Differences.									
Copy of marking plate:									

Page 4 of 4 Report No.: 16-01-07

Те	st item particulars						
Tested lamp:		⊠ continuous wave lamps		pulsed lamps			
Те	sted lamp system						
La	mp classification group (IEC)		☐ risk 1	☐ risk 2	☐ risk 3		
La	mp classification group (EN)	☐ exempt	⊠ risk 1	☐ risk 2	☐ risk 3		
La	mp cap:						
Bu	lb:						
Rated of the lamp:		See Page 1					
Fu	rthermore marking on the lamp						
Se	asoning of lamps according IEC standard						
Us	ed measurement instrument						
Temperature by measurement:		24.0 - 25.0 °C					
Information for safety use:		Not required					
Po	ssible test case verdicts:						
_	test case does not apply to the test object:	N/A					
_	test object does meet the requirement:	P (Pass)					
_	test object does not meet the requirement:	F (Fail)					
Те	sting:						
Date of receipt of test item		2016-01-19					
Date (s) of performance of tests		2016-01-21~2016-01-22					
Ge	neral remarks:						
The test results presented in this report relate only to the object tested.  This report shall not be reproduced, except in full, without the written approval of the Issuing testing laboratory.							

"(See Enclosure #)" refers to additional information appended to the report. "(See appended table)" refers to a table appended to the report. Throughout this report a comma (point) is used as the decimal separator.

List of test equipment must be kept on file and available for review.

## **General product information:**

- PKG: LM101A CCT: 5000K CRI: 80 Flux rank: SE

Tested current : DC 500 mA A photo of test sample.



Throughout this report a comma / point is used as the decimal separator.